

### General Description

The WSD2209DN33 is the highest performance trench P-Channel MOSFETs with extreme high cell density, which provide excellent  $R_{DS(ON)}$  and gate charge for most of the synchronous buck converter applications.

The WSD2209DN33 meet the RoHS and Green Product requirement with full function reliability approved.

### Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Green Device Available

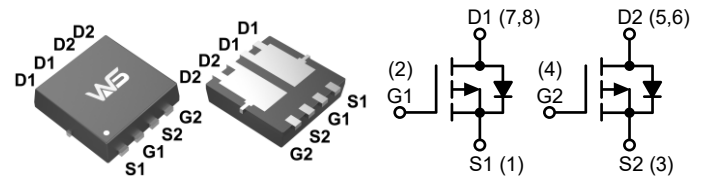
### Product Summary

$BV_{DSS}$	$R_{DS(ON)}$	$I_D$
-20V	28mΩ	-7.5A

### Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

### DFN3X3-8L Pin Configuration



### Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		10s	Steady State	
$V_{DS}$	Drain-Source Voltage	-20		V
$V_{GS}$	Gate-Source Voltage	±10		
$I_D@T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ <sup>1</sup>	-7.5		A
$I_D@T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ <sup>1</sup>	-4.5		
$I_D@T_A=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ <sup>1</sup>	-36	-30	
$I_D@T_A=70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ <sup>1</sup>	-28	-23	
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	-25		
$E_{AS}$	Single Pulse Avalanche Energy <sup>3</sup>	---		mJ
$I_{AS}$	Avalanche Current	---		A
$P_D@T_C=25^\circ C$	Total Power Dissipation <sup>4</sup>	2.5		W
$P_D@T_A=25^\circ C$	Total Power Dissipation <sup>4</sup>	1.6	1.7	
$T_{STG}$	Storage Temperature Range	-55 to 150		°C
$T_J$	Operating Junction Temperature Range	-55 to 150		

**Electrical Characteristics** ( $T_A=25^{\circ}\text{C}$ , Unless Otherwise Noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Units
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-20	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	$BV_{DSS}$ Temperature Coefficient	Reference to $25^{\circ}\text{C}$ , $I_D=-1\text{mA}$	---	-0.132	---	$\text{V}/^{\circ}\text{C}$
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5V, I_D=-4A$	---	28	33	m $\Omega$
		$V_{GS}=-2.5V, I_D=-3A$	---	37	45	
		$V_{GS}=-1.8V, I_D=-2A$	---	50	68	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=-250\mu A$	-0.3	-0.6	-1.0	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	4.4	---	$\text{mV}/^{\circ}\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-20V, V_{GS}=0V, T_J=25^{\circ}\text{C}$	---	---	-1.0	$\mu A$
		$V_{DS}=-20V, V_{GS}=0V, T_J=55^{\circ}\text{C}$	---	---	-5.0	
$I_{GSS}$	Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 8V$	---	10	---	$\mu A$
$g_{fs}$	Forward Transconductance	$V_{DS}=-5V, I_D=-20A$	---	9	---	S
$R_g$	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1.0\text{MHz}$	---	3	---	$\Omega$
$Q_g$	Total Gate Charge (-4.5V)	$V_{DS}=-10V, V_{GS}=-4.5V, I_D=-8A$	---	13.8	17.94	nC
$Q_{gs}$	Gate-Source Charge		---	4.1	5.33	
$Q_{gd}$	Gate-Drain Charge		---	5.6	7.28	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=-10V, V_{GEN}=-4.5V, R_G=3\Omega, I_D=-1A, R_L=0.5\Omega$	---	6.2	---	ns
$T_r$	Rise Time		---	12.7	---	
$T_{d(off)}$	Turn-Off Delay Time		---	51.7	---	
$T_f$	Fall Time		---	16	---	
$C_{iss}$	Input Capacitance	$V_{DS}=-15V, V_{GS}=0V, f=1.0\text{MHz}$	---	1160	---	pF
$C_{oss}$	Output Capacitance		---	104	---	
$C_{rss}$	Reverse Transfer Capacitance		---	29	---	

**Note:**

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 20Z copper,  $t \leq 10\text{sec}$ .
2. The data tested by pulsed, pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$

**Typical Characteristics**

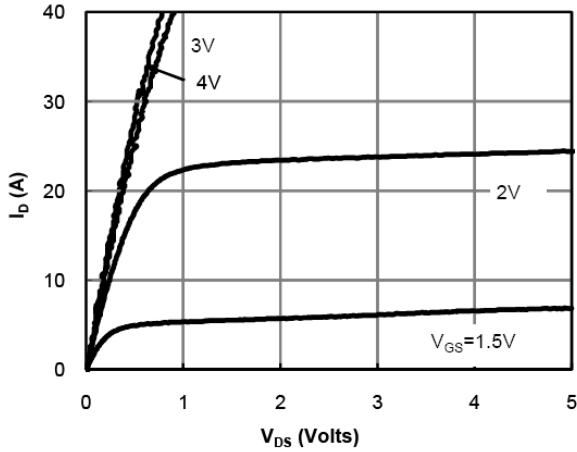


Fig 1: On-Region Characteristics

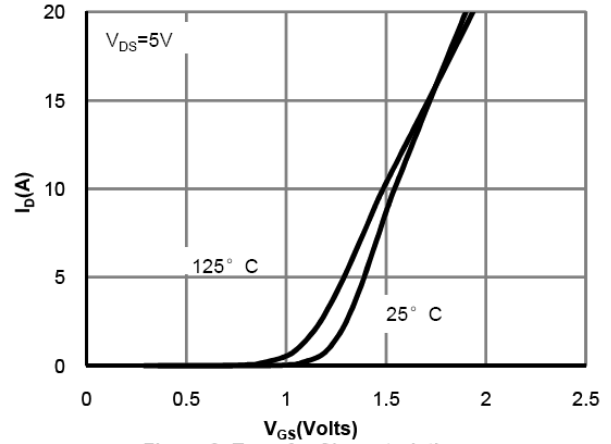


Figure 2: Transfer Characteristics

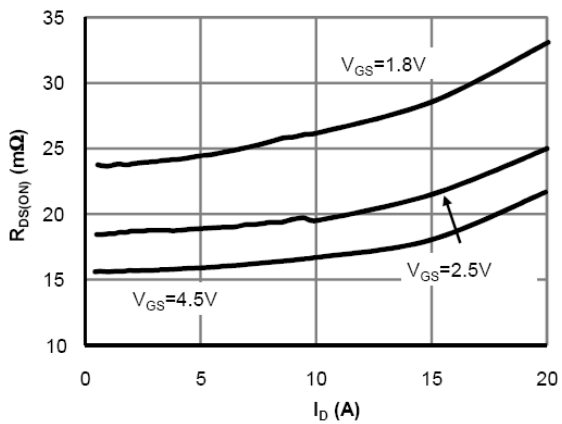


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

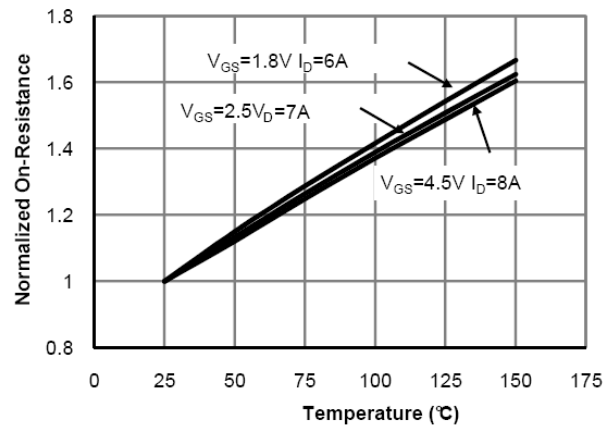


Figure 4: On-Resistance vs. Junction Temperature

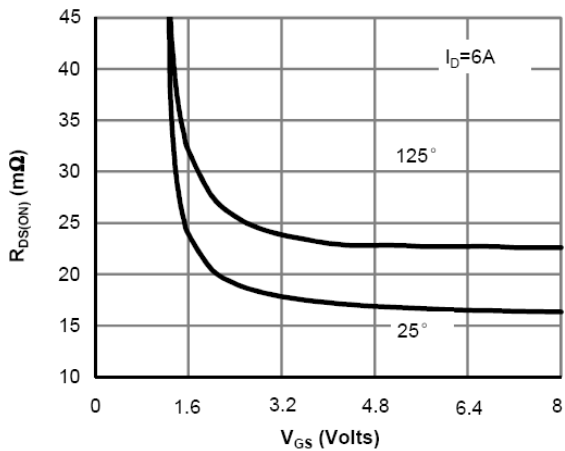


Figure 5: On-Resistance vs. Gate-Source Voltage

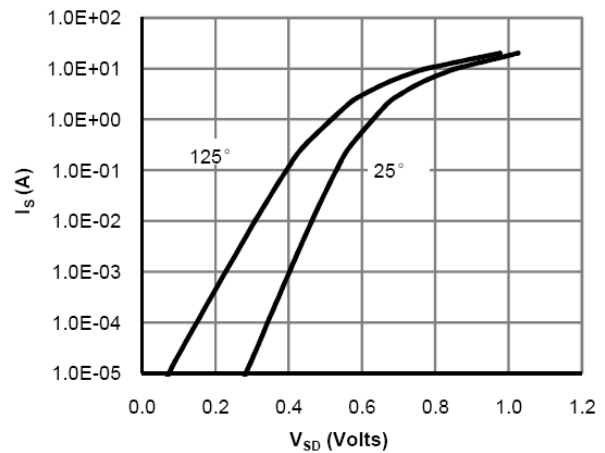


Figure 6: Body-Diode Characteristics

Typical Characteristics (Cont.)

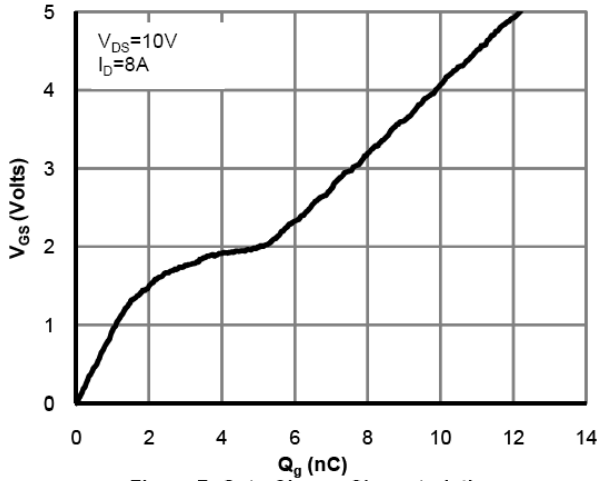


Figure 7: Gate-Charge Characteristics

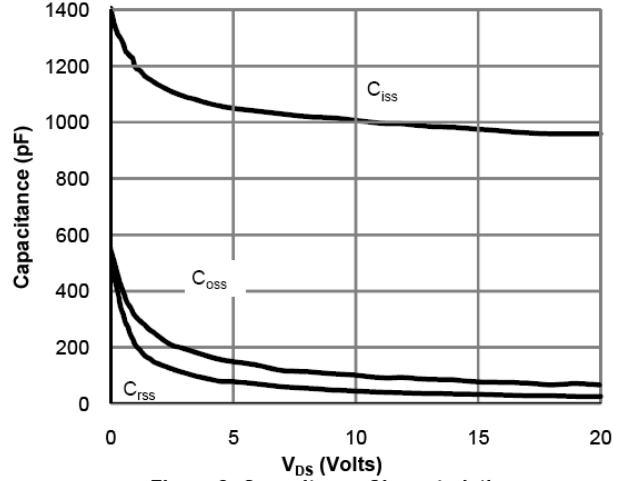


Figure 8: Capacitance Characteristics

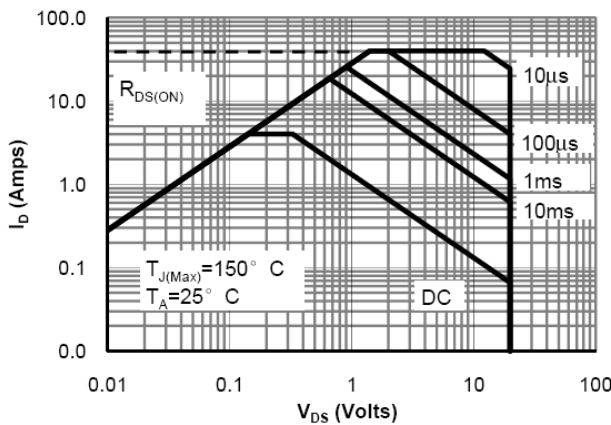


Figure 9: Maximum Forward Biased Safe Operating Area

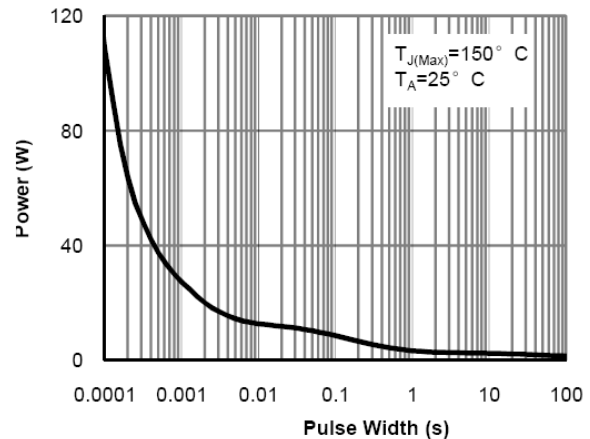


Figure 10: Single Pulse Power Rating Junction-to-Case

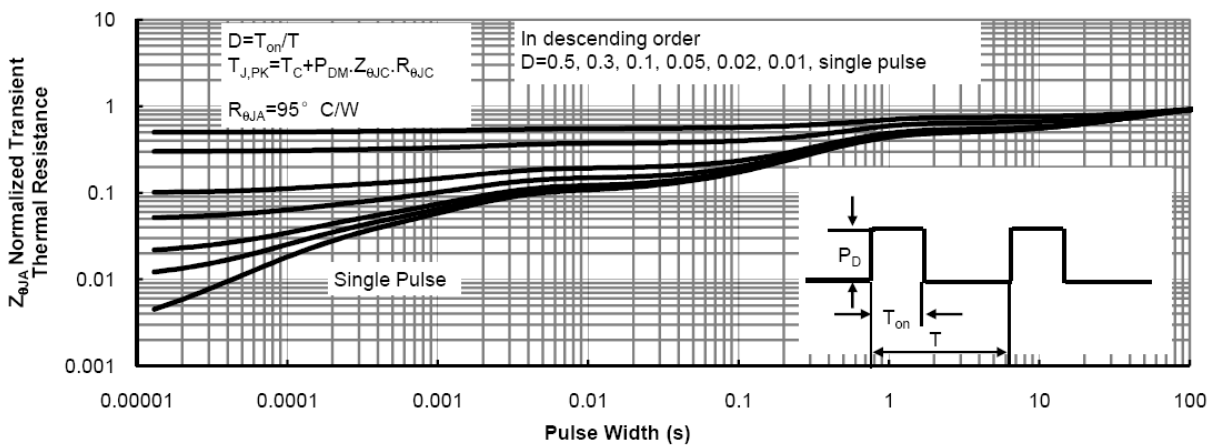
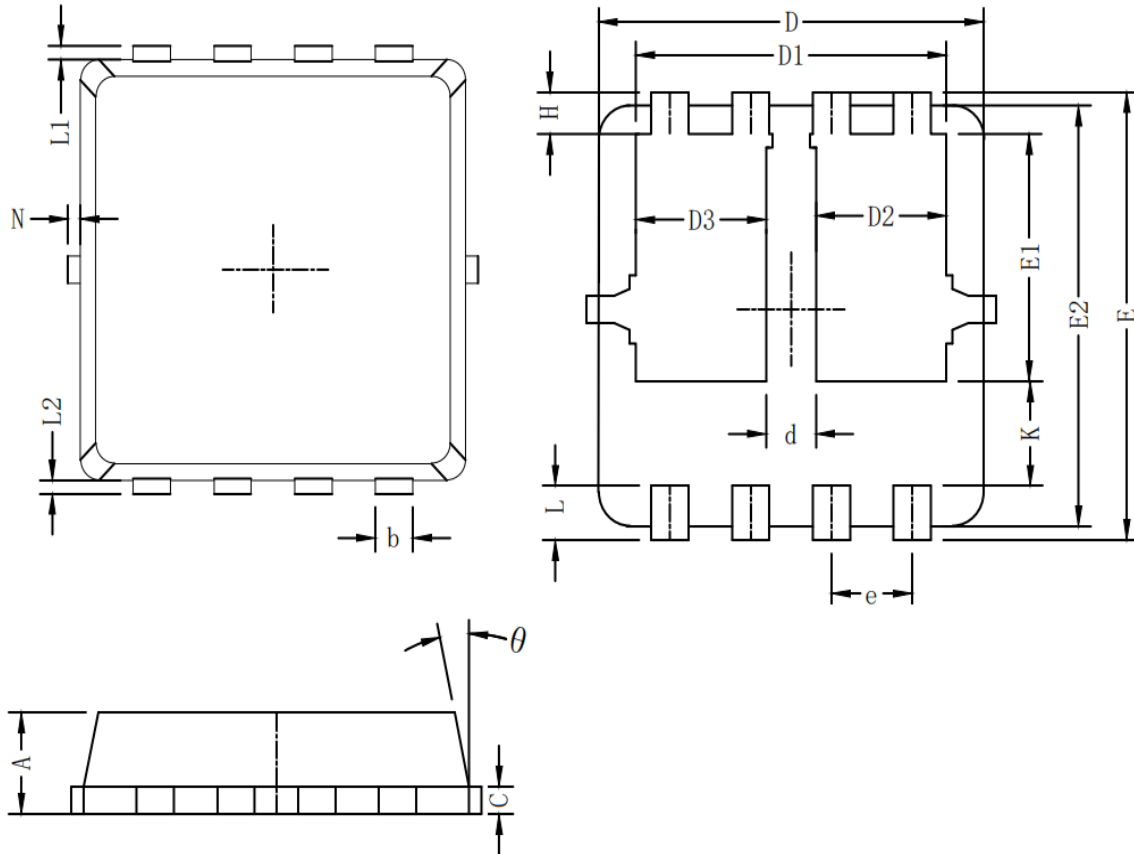


Figure 11: Normalized Maximum Transient Thermal Impedance

**Packaging information**


Symbol	Dim in mm		
	min	typ	max
A	0.6	0.75	0.9
b	0.2	0.3	0.4
C	0.15	0.2	0.25
D	3	3.1	3.2
D1	2.3	2.45	2.6
D2/D3	0.8	1	1.2
E	3.15	3.3	3.45
E1	1.43	1.73	1.93
E2	2.9	3.05	3.2
e	0.65BSC		
H	0.2	0.35	0.5
K	0.57	0.77	0.87
L	0.3	0.4	0.5
L1/L2	0.1REF		
$\theta$	8°	10°	13°
N	0		0.15
d	0.3	0.4	0.5

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